# **PUA3110** (PU3110)

### Silicon NPN triple diffusion planar type

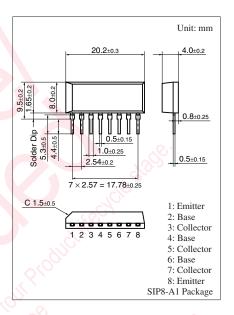
For power amplification/switching Complementary to PUA3210 (PU3210)

#### ■ Features

- High forward current transfer ratio h<sub>FE</sub> which has satisfactory linearity
- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- NPN 3 elements

### ■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	60	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	60	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	6	V	
Collector current	$I_{C}$	3	A	
Peak collector current	$I_{CP}$	5	A	
Base current	$I_B$	1	A	
Collector power dissipation	P <sub>C</sub>	15	W	
$T_a = 25^{\circ}C$		2.4		
Junction temperature	$T_{j}$	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	S°C	

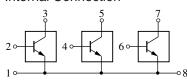


### ■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

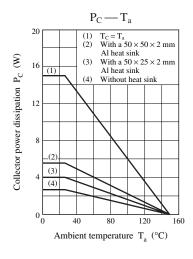
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_C = 30 \text{ mA}, I_B = 0$	60	0///		V
Base-emitter voltage	$V_{BE}$	$V_{CE} = 4 \text{ V}, I_{C} = 3 \text{ A}$	D. 10	5-	1.8	V
Collector-emitter current (E-B short)	$I_{CES}$	$V_{CE} = 60 \text{ V}, V_{BE} = 0$	0,0.		200	μΑ
Collector-emitter cutoff current (Base open)	$I_{CEO}$	$V_{CE} = 30 \text{ V}, I_{B} = 0$			300	μΑ
Emitter-base cutoff current (Collector open)	$I_{EBO}$	$V_{EB} = 6 \text{ V}, I_{C} = 0$			1	mA
Forward current transfer ratio	h <sub>FE1</sub>	$V_{CE} = 4 \text{ V}, I_{C} = 1 \text{ A}$	70		250	_
	h <sub>FE2</sub>	$V_{CE} = 4 \text{ V}, I_{C} = 3 \text{ A}$	10			
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_C = 3 \text{ A}, I_B = 0.375 \text{ A}$			1.2	V
Transition frequency	$f_T$	$V_{CE} = 10 \text{ V}, I_{C} = 0.5 \text{ A}, f = 10 \text{ MHz}$		30		MHz
Turn-on time	t <sub>on</sub>	I <sub>C</sub> = 1 A		0.5		μs
Storage time	t <sub>stg</sub>	$I_{B1} = 0.1 \text{ A}, I_{B2} = -0.1 \text{ A}$		2.5		μs
Fall time	$t_{\rm f}$	$V_{CC} = 50 \text{ V}$		0.4		μs

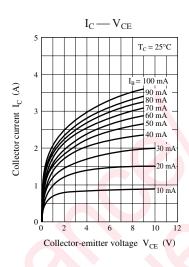
 $Note) \ Measuring \ methods \ are \ based \ on \ JAPANESE \ INDUSTRIAL \ STANDARD \ JIS \ C \ 7030 \ measuring \ methods \ for \ transistors.$ 

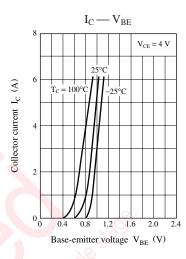
#### ■ Internal Connection

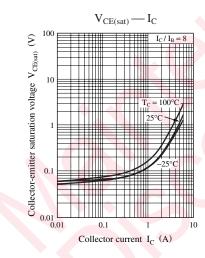


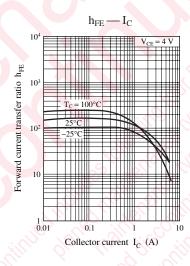
Note) The part number in the parenthesis shows conventional part number.

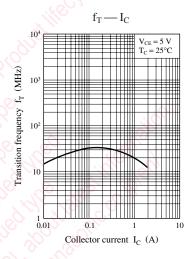


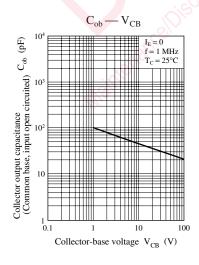


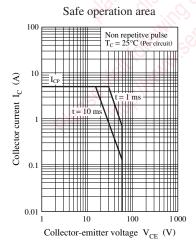












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